


<b>Search Notes</b> 	<b>Application/Control No.</b> 10551817	<b>Applicant(s)/Patent Under Reexamination</b> LIN ET AL.
	<b>Examiner</b> Cheng, Ichieh	<b>Art Unit</b> 4183

SEARCHED			
Class	Subclass	Date	Examiner
455	560,442,449,552.1,331,440,437,456.1,445,438,439	03/03/2008	Ichieh Cheng
370	349,338,329,412,389,469,395.2,236,428,351,436,395.21,401	03/03/2008	Ichieh Cheng

SEARCH NOTES			
Search Notes		Date	Examiner
Text search attached		03/03/2008	Ichieh Cheng

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner